

IGBT3 Power Chip

Features:

- 1700V Trench + Field stop technology
- low switching losses
- soft turn off
- positive temperature coefficient
- easy paralleling

This chip is used for:

• power modules

Applications:

drives



Chip Type	V _{CE}	<i>I</i> _C	Die Size	Package
IGC89T170S8RM	1700V	75A	8.85 x 10.09 mm ²	sawn on foil

Mechanical Parameters

Mechanical Farameters			
Raster size	8.85 x 10.09		
Emitter pad size (incl. gate pad)	6.634 x 7.874		
Gate pad size	1.674 x 0.899	mm ²	
Area total	89.3		
Thickness	190	μm	
Wafer size	200	mm	
Max.possible chips per wafer	280		
Passivation frontside Photoimide			
Pad metal	3200 nm AlSiCu		
Backside metal Ni Ag –system suitable for epoxy and soft solder die bondi			
Die bond	Electrically conductive glue or solder		
Wire bond AI, <500µm			
Reject ink dot size	Ø 0.65mm ; max 1.2mm		
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C		



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, T_{vj} =25 °C	V _{CE}	1700	V	
DC collector current, limited by $T_{\rm vj\;max}$	I _C	1)	А	
Pulsed collector current, t_p limited by $T_{vj max}$	$I_{c,puls}$	225	А	
Gate emitter voltage	V _{GE}	±20	V	
Junction temperature range	T_{vj}	-40 +175	°C	
Operating junction temperature	T_{vj}	-40+150	°C	
Short circuit data $^{2)}$ V_{GE} = 15V, V_{CC} = 1000V, T_{vj} = 150°C	t_{SC}	10	μs	
Reverse bias safe operating area ²⁾ (RBSOA)	$I_{C,max} = 150A, V_{CE,max} = 1700V$ $T_{vj} \le 150^{\circ}C$			

¹⁾ depending on thermal properties of assembly

Static Characteristic (tested on wafer), $T_{\rm vj}$ =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter			min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ = 2 mA	1700			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =75A	1.6	1.9	2.2	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =3mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.2	5.8	6.4	
Zero gate voltage collector current	I _{CES}	V _{CE} =1700V , V _{GE} =0V			4	μA
Gate-Emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			300	nA
Integrated gate resistor	$r_{\rm G}$			8.5		Ω

Dynamic Characteristic (not subject to production test - verified by design / characterization), T_{v_i} =25 °C

Parameter	Symbol	Conditions	Value			Unit
raiametei	Symbol	Conditions	min.	typ.	max.	Julii
Input capacitance	Cies	V _{CE} =25V,		6800		
Reverse transfer capacitance	C _{res}	$V_{GE}=0V$, f=1MHz		220		pF

²⁾ not subject to production test - verified by design/characterization

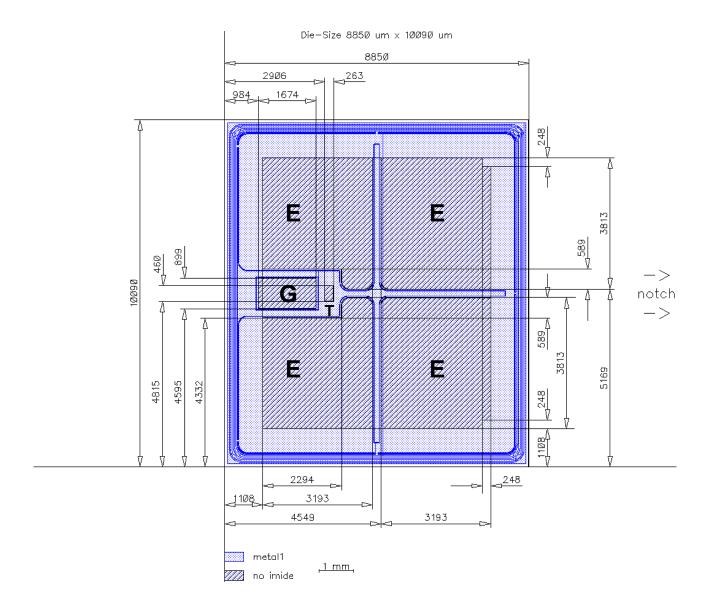


Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing



E = Emitter

G = Gate

T = Test pad do not contact



Description
AQL 0,65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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